

**Notice of References Cited**

Application/Control No.

10/520,777

Applicant(s)/Patent Under

Reexamination

WANG ET AL.

Examiner

Chih-Cheng Glen Kao

Art Unit

2882

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-			
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Fu et al., "Monitoring the anomalous scattering signal and noise levels in X-ray diffraction of crystals", Acta Crystallographica: Section D, March 2004, Volume 60, Issue 3, pp. 499-506.
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.